

Electronic and magnetic order as a function of doping in mixed-valent La_{1-x}Sr_xMnO₃ thin films



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Molecular Beam Epitaxy

- Our samples were grown using a technique known as Molecular Beam Epitaxy (MBE).
- In MBE, we utilize carefully calibrated molecular beams of constituent elements to produce thin films one atomic layer at a time
- Sources of the constituent elements are heated in effusion cells to evaporate material into the chamber, forming molecular beams.

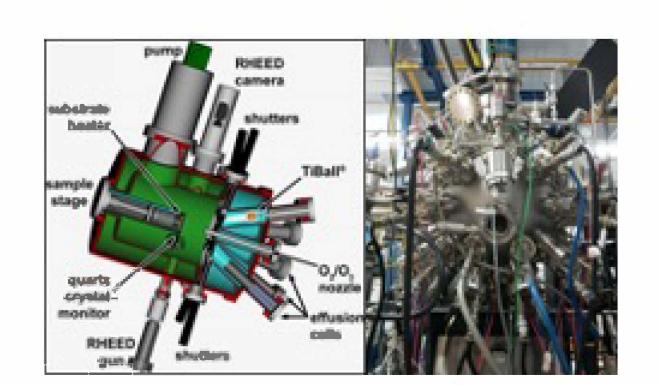


Fig. 1 (Left) A side view diagram of an MBE chamber. (Right) A front view picture of the chamber used in our growths.

- In oxide MBE, a form of oxygen is introduced into the chamber to form oxides.
- For our growths of La_{1-x}Sr_xMnO₃, ozone was employed as our source of oxygen, allowing us to keep the chamber pressure low (5E-7 Torr) due to ozone's high oxidizing potential.

Bulk Phase Behavior

- The behavior of La₁.
 _xSr_xMnO₃ has been extensively documented in bulk crystals with respect to temperature and strontium concentration.
- Undoped LaMnO₃ is known to be a Mott insulator that at higher
- La, Sr MnO₃

 eg

 eg

 eg

 Mn³⁺ (d⁴)

 Mn⁴⁺ (d³)

Fig. 3 (Top) The phase diagram of La_{1-x}Sr_xMn●₃ in bulk.¹ (Bottom) Mechanism for the double exchange interaction.

- temperatures has paramagnetic behavior and becomes antiferromagnetic at lower temperatures.
- In the range around x=0.4 La_{1-x}Sr_xMnO₃ is a paramagnetic insulator at higher temperatures but at lower temperatures it transitions to a ferromagnetic conductor.
- This ferromagnetic-conducting state is kinetically favorable around x=0.4
 at lower temperatures because the double exchange interaction allows for
 the delocalization of electrons across spin aligned manganese atoms,
 reducing free energy.

Reference

[1]Hemberger et al, PRB 66, 094410 (2002).

Thin Films of La_{1-x}Sr_xMnO₃ for Different Doping Concentrations

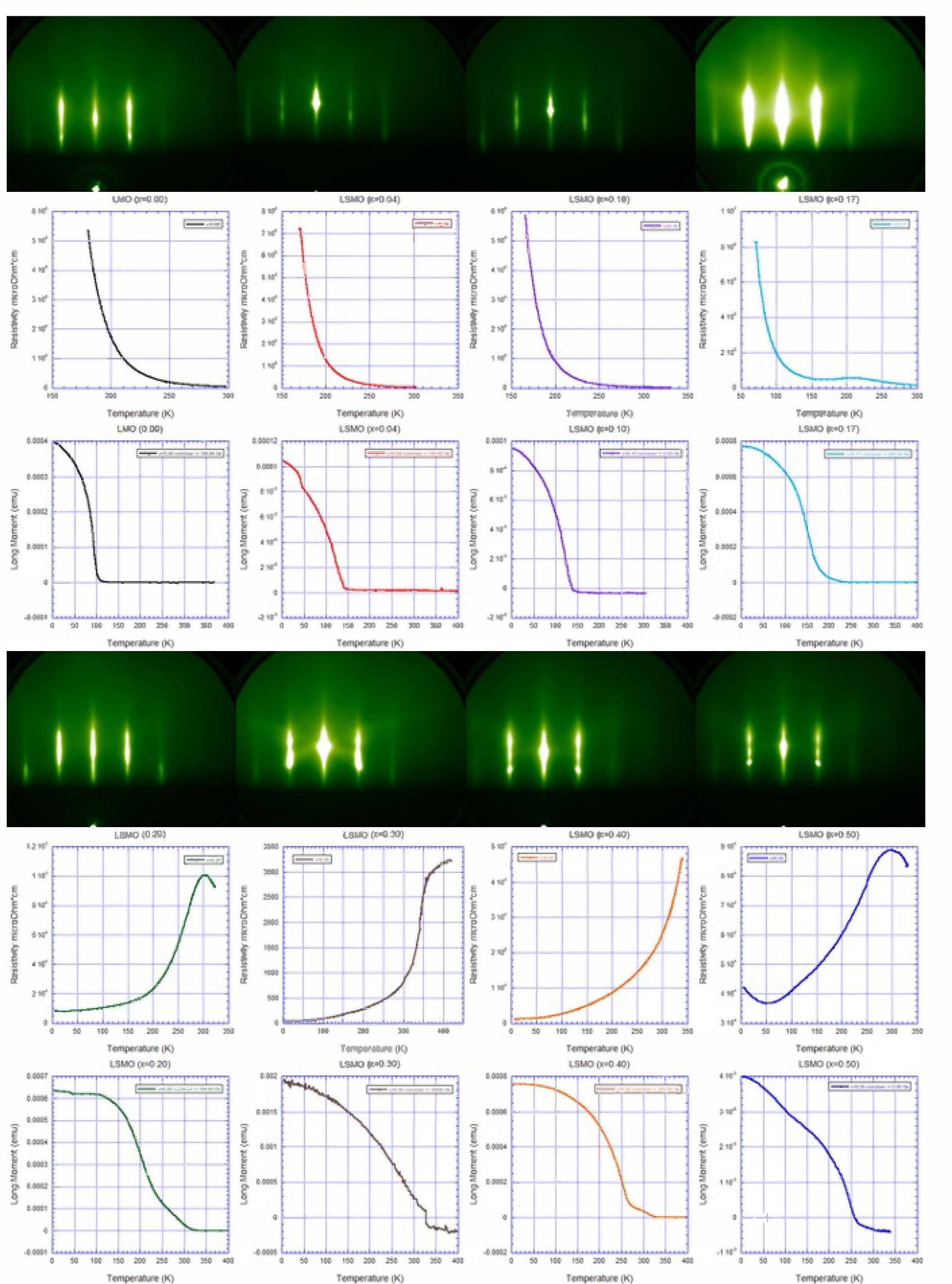


Fig. 5 (Top) Reflection high energy electron diffraction (RHEED) patterns taken during the growth of each sample (x=0, 0.04, 0.10, 0.17, 0.20, 0.30, 0.40, 0.50). (Middle) The measure of film resistivity as a function of temperature for each sample. (Bottom) The measure of film magnetic field, collected in a field cooldown, as a function of temperature for each sample.

An atomic force
microscopy scan was
done for the x=0.30 film.
In this scan, figure 4,
terraces can be seen in
the surface morphology,
which is indicative that
the film is flat and
strained to the substrate.

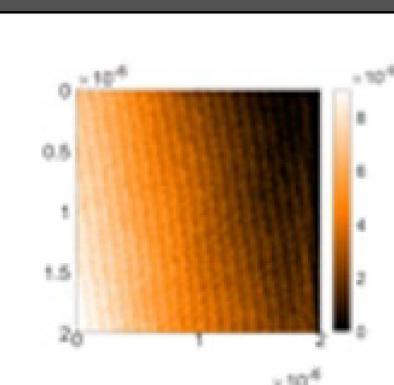


Fig. 4 Atomic force microscopy (AFM) image of the surface of the x=0.3 sample.

- Additionally, Reflection high energy electron diffraction (RHEED) patterns taken near the end of the growths, shown in figure 5, also indicate well-strained growth and a 2-dimensional surface morphology.
- From the film transport and magnetic data, figure 5 and 6, we can observe transitions in the in the electronic and magnetic ordering of the samples.
- Samples x=0, 0.04, and 0.10 are shown to be insulators over the entire temperature range measured, with magnetic ordering in the x=0 sample below around 100K and below 140K for the x=0.04 and 0.10 samples.
- In x=0.20, 0.30, and 0.40 we observe a ground state conducting behavior, while insulating behavior is present below 50K in x=0.50 and 170K in x=0.17
- A metal-to-insulator transition accompanied by magnetic ordering is observed below around: 210K for x=0.17, 310K for x=0.20, 400K for x=0.30, and 260K for x=0.50. We also observe magnetic ordering in x=0.4 below around 320K though no metal-to-insulator transition is observed within the measured range.

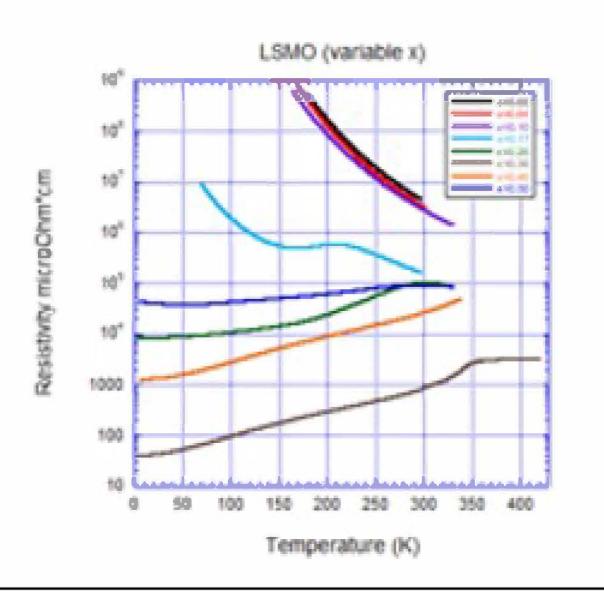


Fig. 6 Film resistivity as a function of temperature for x=0, 0.04, 0.10, 0.17, 0.20, 0.30 0.40 and 0.50 compared on a log scale.